



SN65HVD251-Q1

SLLS788-APRIL 2007

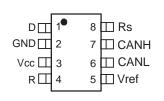
CAN TRANSCEIVER

FEATURES

- Qualified for Automotive Applications
- **Drop-In Improved Replacement for the** PCA82C250 and PCA82C251
- Bus-Fault Protection of ±36 V •
- Meets or Exceeds ISO 11898 •
- Signaling Rates⁽¹⁾ up to 1 Mbps •
- High Input Impedance Allows up to 120 • SN65HVD251 Nodes on a Bus
- Bus Pins ESD Protection Exceeds 9 kV (HBM) •
- **Unpowered Node Does Not Disturb the Bus**
- Low-Current Standby Mode: 200 µA Typical •
- **Thermal Shutdown Protection** •
- **Glitch-Free Power-Up and Power-Down Bus** . Protection for Hot Plugging
- DeviceNet[™] Vendor ID #806 .
- (1) The signaling rate of a line is the number of voltage transitions that are made per second expressed in bps (bits per second).

APPLICATIONS

- CAN Data Buses
- **Industrial Automation**
 - DeviceNet Data Buses
 - Smart Distributed Systems (SDS[™])
- SAE J1939 Standard Data Bus Interface •
- NMEA 2000 Standard Data Bus Interface
- ISO 11783 Standard Data Bus Interface



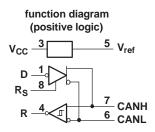
DESCRIPTION

The SN65HVD251 is intended for use in applications employing the Controller Area Network (CAN) serial communication physical layer in accordance with the ISO 11898 Standard. The SN65HVD251 provides differential transmit capability to the bus and differential receive capability to a CAN controller at speeds up to 1 megabit per second (Mbps).

Designed for operation in harsh environments, the device features crosswire, overvoltage, and loss of ground protection to ±36 V. Also featured are overtemperature protection as well as -7-V to 12-V common-mode range, and tolerance to transients of ±200 V. The transceiver interfaces the single-ended CAN controller with the differential CAN bus found in industrial, building automation, and automotive applications.

Rs, pin 8, selects one of three different modes of operation: high-speed, slope control, or low-power mode. The high-speed mode of operation is selected by connecting pin 8 to ground, allowing the transmitter output transistors to switch as fast as possible with no limitation on the rise and fall slope. The rise and fall slope can be adjusted by connecting a resistor to ground at pin 8; the slope is proportional to the pin's output current. Slope control with an external resistor value of 10 k Ω gives ~15 V/µs slew rate; 100 k Ω gives ~2 V/µs slew rate.

If a high logic level is applied to the Rs pin 8, the device enters a low-current standby mode where the driver is switched off and the receiver remains active. The local protocol controller returns the device to the normal mode when it transmits to the bus.





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SN65HVD251-Q1



SLLS788-APRIL 2007



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

ORDERING INFORMATION⁽¹⁾

PART NUMBER	PACKAGE	MARKED AS
SN65HVD251QDRQ1	8-pin SOIC (Tape and Reel)	251Q1

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)⁽¹⁾⁽²⁾

			SN65HVD251
Supply voltage range, V_{CC}			–0.3 V to 7 V
Voltage range at any bus terminal		CANH, CANL	-36 V to 36 V
Transient voltage per ISO 7637, puls	se 1, 2, 3a, 3b	CANH, CANL	±200 V
Input voltage range, V _I		D, Rs, R	–0.3 V to V _{CC} + 0.5
Receiver output current, I _O			-10 mA to 10 mA
	Human-Body Model (3)	CANH, CANL, GND	9 kV
Flastrastatia disabarga	Human-Body Model	All pins	6 kV
Electrostatic discharge	Charged-Device Model (4)	All pins	1 kV
	Machine Model	All pins	200 V
Continuous total power dissipation	·		See Dissipation Rating Table

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

(3) Tested in accordance with JEDEC Standard 22, Test Method A114-A

(4) Tested in accordance with JEDEC Standard 22, Test Method C101

ABSOLUTE MAXIMUM POWER DISSIPATION RATINGS

PACKAGE	CIRCUIT BOARD MODEL	T _A = 25°C POWER RATING	DERATING FACTOR ⁽¹⁾ ABOVE $T_A = 25^{\circ}C$	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
	Low-K ⁽²⁾	576 mW	4.8 mW/°C	288 mW	96 mW
SOIC (D)	High-K ⁽³⁾	924 mW	7.7 mW/°C	462 mW	154 mW

(1) This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

(2) In accordance with the Low-K thermal metric definitions of EIA/JESD51-3

(3) In accordance with the High-K thermal metric definitions of EIA/JESD51-7

THERMAL CHARACTERISTICS

PARAMETER		TEST CONDITIONS	S VALUE			UNIT
			MIN	TYP	MAX	
θ_{JB}	Junction-to-board thermal resistance			78.7		°C/W
θ_{JC}	Junction-to-case thermal resistance			44.6		°C/W
6		$V_{CC} = 5 \text{ V}, \text{ T}_{J} = 27^{\circ}\text{C}, \text{ R}_{L} = 60 \Omega,$ $\text{R}_{S} \text{ at 0 V}, \text{ Input to D a 500-kHz}$ 50% duty cycle square wave			97.7	mW
P _D	Device power dissipation	$\label{eq:V_CC} \begin{array}{l} V_{CC} = 5.5 \mbox{ V}, \mbox{ T}_{J} = 130^{\circ}\mbox{C}, \mbox{ R}_{L} = 60 \ \Omega, \\ \mbox{ R}_{S} \mbox{ at } 0 \mbox{ V}, \mbox{ Input to } D \mbox{ a } 500\mbox{-}\mbox{kHz } 50\% \\ \mbox{ duty cycle square wave} \end{array}$			142	mW
T_{SD}	Thermal shutdown junction temperature			165		°C

RECOMMENDED OPERATING CONDITIONS

over recommended operating conditions (unless otherwise noted)

PARAMETER		MIN	NOM MAX	UNIT
Supply voltage, V _{CC}		4.5	5.5	V
Voltage at any bus terminal (separately or commo	n mode) V _I or V _{IC}	-7 ⁽¹⁾	12	V
High-level input voltage, V _{IH}	D input	0.7 V _{CC}		V
Low-level input voltage, VIL	D input		0.3 V _{CC}	V
Differential input voltage, V _{ID}		-6	6	V
Input voltage to Rs, V _{I(Rs)}		0	V _{CC}	V
Input voltage at Rs for standby, $V_{I(Rs)}$		0.75 V _{CC}	V _{CC}	V
Rs wave-shaping resistance		0	100	kΩ
	Driver	-50		mA
High-level output current, I _{OH}	Receiver	-4		IIIA
	Driver		50	… ^
Low-level output current, I _{OL} Receiver			4	mA
Operating free-air temperature, T _A		-40	125	°C
Junction temperature, T _j			145	°C

(1) The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
	Bus output voltage	CANH	Figure 1 and Figure 2, D at 0 V,	2.75	3.5	4.5	
V _{O(D)}	(Dominant)	CANL	Rs at 0 V	0.5		2	
	Bus output voltage	CANH	Figure 1 and Figure 2, D at 0.7 V_{CC} ,		2.5	3	V
V _{O(R)}	(Recessive)	CANL	Rs at 0 V	2	2.5	3	
V _{OD(D)}	Differential output voltage	e (Dominant)	Figure 1, D at 0 V, Rs at 0 V	1.5	2	3	V
V _{OD(D)}	Differential output voltag	e (Dominant)	Figure 2 and Figure 3, D at 0 V, Rs at 0 V	1.2	2	3.1	V
V _{OD(R)}	Differential output voltage	e (Recessive)	Figure 1 and Figure 2, D at 0.7 V _{CC}	-120		12	mV
V _{OD(R)}	Differential output voltag	e (Recessive)	D at 0.7 V _{CC} , No load	-0.5		0.05	V
V _{OC(pp)}	Peak-to-peak common-mode output voltage		Figure 9, Rs at 0 V		600		mV
I _{IH}	High-level input current,	D input	D at 0.7 V _{CC}	-40		0	μA
IIL	Low-level input current, I) input	D at 0.3 V _{CC}	-60		0	μA
			Figure 11, V _{CANH} at –7 V, CANL open	-200			
	Chart aircuit ataadu atata		Figure 11, V _{CANH} at 12 V, CANL open			2.5	mA
I _{OS(SS)}	Short-circuit steady-state	oulput current	Figure 11, V _{CANL} at –7 V, CANH open	-2			mA
			Figure 11, V _{CANL} at 12 V, CANH open			200	
Co	Output capacitance		See receiver input capacitance				
I _{OZ}	High-impedance output of	current	See receiver input current				
I _{IRs(s)}	Rs input current for standby		Rs at 0.75 V _{CC}	-10			μA
I _{IRs(f)}	Rs input current for full-s	peed operation	Rs at 0 V	-550		0	μA
		Standby	Rs at V _{CC} , D at V _{CC}			275	μA
I _{CC}	Supply current	Dominant	D at 0 V, 60- Ω load, Rs at 0 V			65	m۸
	Recessive		D at V _{CC} , No load, Rs at 0 V			14	mA

(1) All typical values are at 25° C and with a 5-V supply.

DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
		Figure 4, Rs at 0 V		40	70		
t _{pLH}	Propagation delay time, low-to-high-level output	Figure 4, Rs with 10 k Ω to ground		90	125	ns	
		Figure 4, Rs with 100 k Ω to ground		500	800		
		Figure 4, Rs at 0 V		85	125		
t _{pHL}	Propagation delay time, high-to-low-level output	Figure 4, Rs with 10 k Ω to ground		200	260	ns	
-		Figure 4, Rs with 100 k Ω to ground		1150	1450		
		Figure 4, Rs at 0 V		45	85		
t _{sk(p)}	$x_{(p)}$ Pulse skew ($ t_{pHL} - t_{pLH} $)	Pulse skew (t _{pHL} - t _{pLH})	Figure 4, Rs with 10 k Ω to ground		110	180	ns
		Figure 4, Rs with 100 k Ω to ground		650	900		
t _r	Differential output signal rise time		35		100	ns	
t _f	Differential output signal fall time	Figure 4, Rs at 0 V	35		100	ns	
t _r	Differential output signal rise time		100		250	ns	
t _f	Differential output signal fall time	Figure 4, Rs with 10 k Ω to ground	100		250	ns	
t _r	Differential output signal rise time		600		1550	ns	
t _f	Differential output signal fall time	Figure 4, Rs with 100 k Ω to ground	600		1550	ns	
t _{en}	Enable time from standby to dominant	Figure 8			0.5	μs	

RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETE	ER	TEST CONDI	TIONS	MIN	TYP	MAX	UNIT
V _{IT+}	Positive-going input	threshold voltage				750	900	
V _{IT}	Negative-going input	threshold voltage	Rs at 0 V, (See Table 1)		500	650		mV
V _{hys}	Hysteresis voltage (V	/ _{IT+} – V _{IT–})				100		
VOH	High-level output vol	tage	Figure 6, $I_0 = -4 \text{ mA}$		0.8 V _{CC}			V
V _{OL}	Low-level output volt	age	Figure 6, I _O = 4 mA				0.2 V _{CC}	V
			CANH or CANL at 12 V				600	
	Due insut summer		CANH or CANL at 12 V, V_{CC} at 0 V	Other bus pin at			715	
IJ	Bus input current	CANH or CANL at -7 V	0 V, Rs at 0 V, D at 0.7 V _{CC}	-460			A	
			CANH or CANL at –7 V, V_{CC} at 0 V		-340			
CI	Input capacitance (C	ANH or CANL)	Pin-to-ground, $V_I = 0.4 \sin D$ at 0.7 V_{CC}	(4E6πt) + 0.5 V,		20		pF
C _{ID}	Differential input cap	acitance	Pin-to-pin, $V_I = 0.4 \sin (4E6)$ D at 0.7 V _{CC}	δπt) + 0.5 V,		10		pF
R _{ID}	Differential input resi	stance	D at 0.7 V _{CC} , Rs at 0 V		40		100	kΩ
R _{IN}	Input resistance (CA	NH or CANL)	D at 0.7 V _{CC} , Rs at 0 V		20		50	kΩ
		Standby	Rs at V _{CC,} D at V _{CC}				275	А
I _{CC}	Supply current	Dominant	D at 0 V, 60-Ω load, Rs at	0 V			65	
		Recessive	D at V _{CC} , No load, Rs at 0	V			14	mA

RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{pLH}	Propagation delay time, low-to-high-level output			35	50	ns
t _{pHL}	Propagation delay time, high-to-low-level output			35	50	ns
t _{sk(p)}	Pulse skew (t _{pHL} – t _{pLH})	Figure 6			20	ns
t _r	Output signal rise time			2	4	ns
t _f	Output signal fall time			2	4	ns
t _{p(sb)}	Propagation delay time in standby	Figure 12, Rs at V _{CC}			500	ns

VREF PIN CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

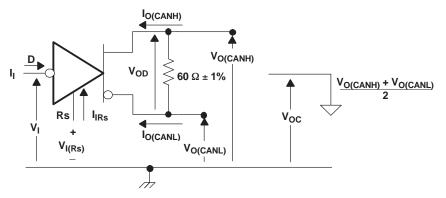
	PARAMETER	TEST CONDITIONS	MIN	MAX	UNIT
Ĩ		–5 μA < I _O < 5 μA	0.45 V _{CC}	0.55 V _{CC}	V
	V _O Reference output voltage	–50 μA < I _O < 50 μA	0.4 V _{CC}	0.6 V _{CC}	v

DEVICE SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		Figure 10, Rs at 0 V		60	100	
t _{loop1}	Total loop delay, driver input to receiver output, recessive to dominant	Figure 10, Rs with 10 k Ω to ground		100	150	ns
		Figure 10, Rs with 100 k Ω to ground		440	800	
		Figure 10, Rs at 0 V		115	150	
t _{loop2}	Total loop delay, driver input to receiver output, dominant to recessive	Figure 10, Rs with 10 k Ω to ground		235	290	ns
	Supu, dominant to recessive	Figure 10, Rs with 100 k Ω to ground		1070	1450	
t _{loop2}	Total loop delay, driver input to receiver output, dominant to recessive	Figure 10, Rs at 0 V, V_{CC} from 4.5 V to 5.1 V		105	145	ns

PARAMETER MEASUREMENT INFORMATION





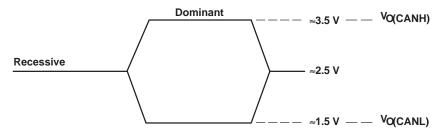


Figure 2. Bus Logic State Voltage Definitions

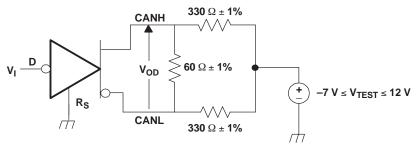


Figure 3. Driver V_{OD}

PARAMETER MEASUREMENT INFORMATION (continued)

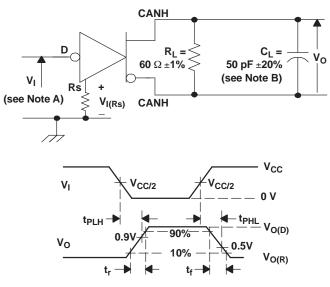
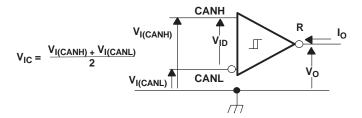
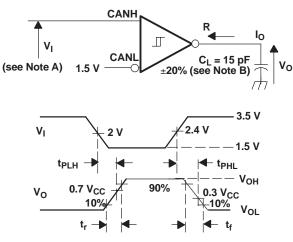


Figure 4. Driver Test Circuit and Voltage Waveforms





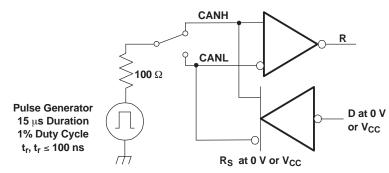


- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_r \leq 6ns$, $t_f \leq 6$ ns, $Z_O = 50 \Omega$.
- B. C_L includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 6. Receiver Test Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION (continued)



A. This test is conducted to test survivability only. Data stability at the R output is not specified.

Figure 7. Test Circuit, Transient Overvoltage Test

Table 1. Receiver Characteristics Over Common Mode Voltage

IND	UT.	MEACUDED		DUT
INP	01	MEASURED	001	PUT
V _{CANH}	V _{CANL}	V _{ID}	l	R
12 V	11.1 V	900 mV	L	
–6.1 V	-7 V	900 mV	L	
-1 V	-7 V	6 V	L	V _{OL}
12 V	6 V	6 V	L	
-6.5 V	-7 V	500 mV	Н	
12 V	11.5 V	500 mV	Н	
-7 V	–1 V	6 V	Н	V _{OH}
6 V	12 V	6 V	Н	1
open	open	Х	Н	1

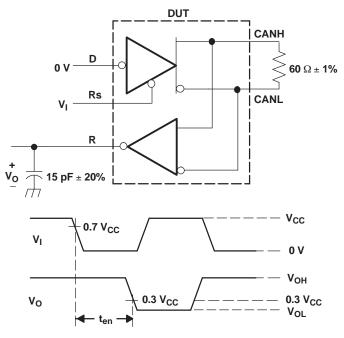
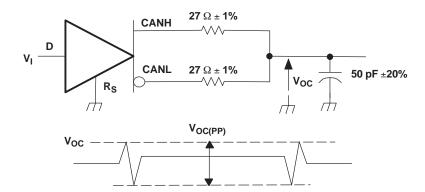


Figure 8. t_{en} Test Circuit and Voltage Waveforms



A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_r \leq 6$ ns, $t_f \leq 6$ ns, $Z_O = 50 \Omega$.

Figure 9. Peak-to-Peak Common Mode Output Voltage

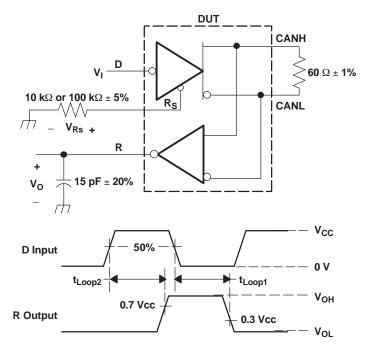


Figure 10. t_{LOOP} Test Circuit and Voltage Waveforms

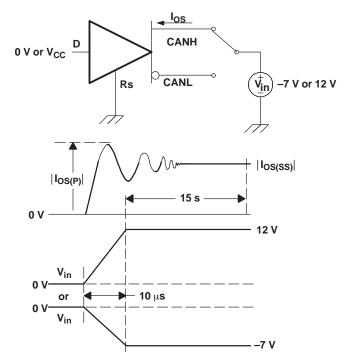
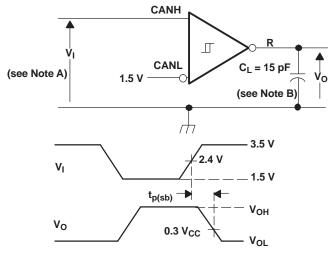


Figure 11. Driver Short-Circuit Test



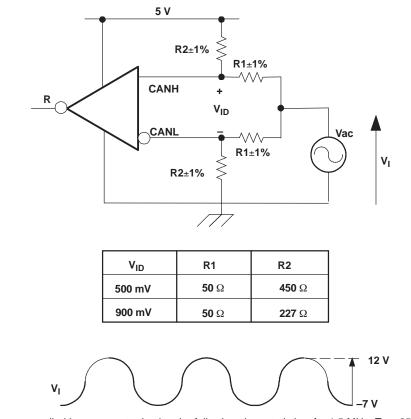
- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 125 kHz, 50% duty cycle, $t_f \leq 6$ ns, $t_f \leq 6$ ns, $Z_O = 50 \Omega$.
- B. C_L includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 12. Receiver Propagation Delay in Standby Test Circuit and Waveforms

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DEVICE INFORMATION



A. All input pulses are supplied by a generator having the following characteristics: f < 1.5 MHz, $T_A = 25^{\circ}C$, $V_{CC} = 5$ V.

Figure 13. Common-Mode Input Voltage Rejection Test

FUNCTION TABLES

Table 2. DRIVER

INPUTS	Veltere et P. V	OUT	BUS STATE		
D	Voltage at R _s , V _{Rs}	CANH	CANL	BUS STATE	
L	V _{Rs} < 1.2 V	Н	L	Dominant	
Н	V _{Rs} < 1.2 V	Z	Z	Recessive	
Open	Х	Z	Z	Recessive	
Х	V _{Rs} > 0.75 V _{CC}	Z	Z	Recessive	

Table 3. RECEIVER

DIFFERENTIAL INPUTS [V _{ID} = V(CANH) – V(CANL)]	OUTPUT R ⁽¹⁾
$V_{ID} \ge 0.9 V$	L
0.5V < V _{ID} < 0.9 V	?
$V_{ID} \leq 0.5 V$	Н
Open	Н

(1) H = high level; L = low level; X = irrelevant; ? = indeterminate; Z = high impedance

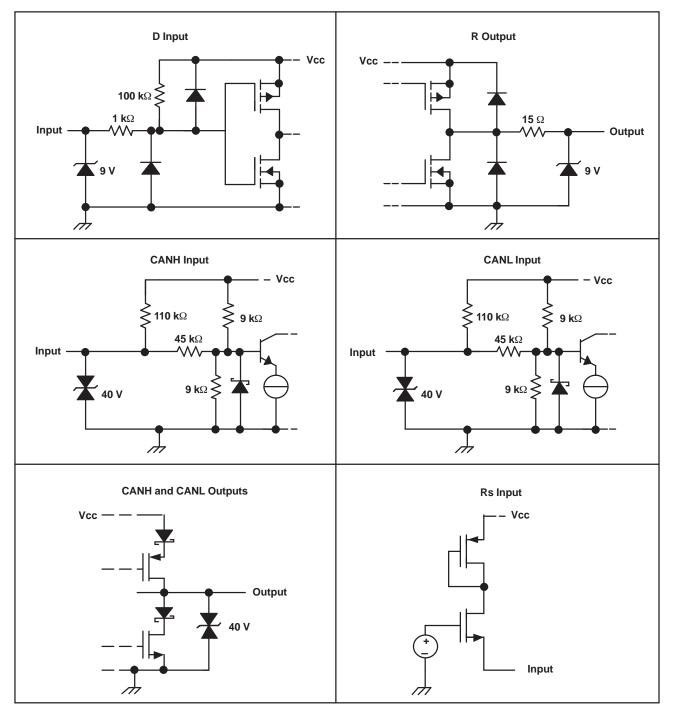


Figure 14. Equivalent Input and Output Schematic Diagrams

t_{LOOP1} – LOOP TIME

vs FREE-AIR TEMPERATURE

V_{CC} = 4.5 V

V_{CC} = 5.5 V

110 125

20 35 50 65 80 95

T_A – Free-Air Temperature – °C

Figure 15.

DRIVER LOW-LEVEL OUTPUT CURRENT

VS LOW-LEVEL OUTPUT VOLTAGE

2

VoCANL - Low-Level Output Voltage - V

Figure 18.

3

4

5

SLLS788-APRIL 2007

74

72

70

68

66

64

62

140

120

100

80

60

40

20

0

0

Driver Low-Level Output Current – mA

Ч

-40-25-10 5

 $V_{CC} = 5 V_{,}$

 $T_A = 25^{\circ}C$,

 $R_S = 0 V,$

D at 0V

LOOP1 - Loop Time - ns

 $R_S = 0 V$

 $V_{CC} = 5 V$



t_{LOOP2} – LOOP TIME

FREE-AIR TEMPERATURE

 $V_{CC} = 5 V$

V_{CC} = 5.5 V

V_{CC} = 4.5 V

-40-25-10 5 20 35 50 65 80 95 110 125

 $T_A-Free-Air$ Temperature – $^\circ C$

Figure 16.

DRIVER HIGH-LEVEL OUTPUT CURRENT

VS HIGH-LEVEL OUTPUT VOLTAGE

 $V_{CC} = 5 V_{,}$

 $T_A = 25^{\circ}C$,

 $R_S = 0 V$,

D at 0V

150

14

140

135

130

125

120

80

70

60

50

40

30

20

10

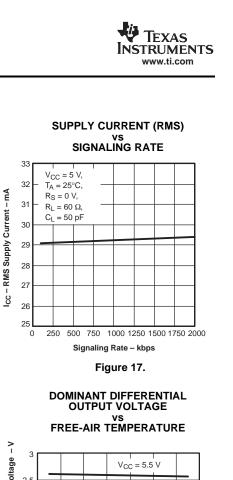
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0

l_{OH} – Driver High-Level Output Current – mA

tLOOP2 - Loop Time - ns

 $R_S = 0 V$



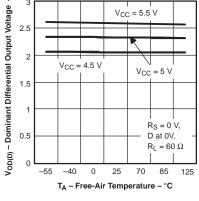
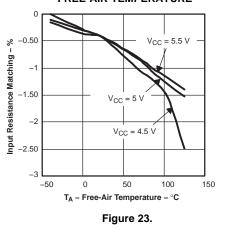


Figure 20.

INPUT RESISTANCE MATCHING FREE-AIR TEMPERATURE



5 VoCANH – High-Level Output Voltage – V

Figure 19.

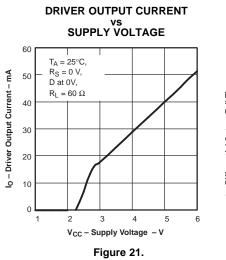
DIFFERENTIAL OUTPUT

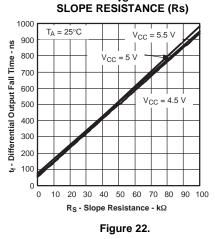
FALL TIME

2

3

4





Submit Documentation Feedback

APPLICATION INFORMATION

The basics of bus arbitration require that the receiver at the sending node designate the first bit as dominant or recessive after the initial wave of the first bit of a message travels to the most remote node on a network and back again. Typically, this *sample* is made at 75% of the bit width, and within this limitation, the maximum allowable signal distortion in a CAN network is determined by network electrical parameters.

Factors to be considered in network design include the 5 ns/m propagation delay of typical twisted-pair bus cable; signal amplitude loss due to the loss mechanisms of the cable; and the number, length, and spacing of drop-lines (stubs) on a network. Under strict analysis, variations among the different oscillators in a system must also be accounted for with adjustments in signaling rate and stub and bus length. Table 4 lists the maximum signaling rates achieved with the SN65HVD251 in high-speed mode with several bus lengths of category 5, shielded twisted-pair (CAT 5 STP) cable.

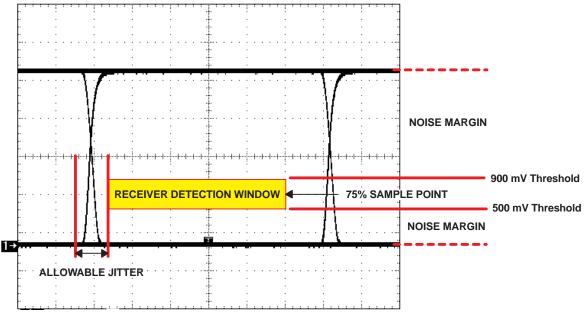
Table 4. Maximum Signaling Rates for VariousCable Lengths

BUS LENGTH (m)	SIGNALING RATE (kbps)
30	1000
100	500
250	250
500	125
1000	62.5

The ISO 11898 standard specifies a maximum bus length of 40 m and maximum stub length of 0.3 m with a maximum of 30 nodes. However, with careful design, users can have longer cables, longer stub lengths, and many more nodes on a bus. (Note: Non-standard application may come with a trade-off in signaling rate.) A bus with a large number of nodes requires a transceiver with high input impedance such as the HVD251.

The Standard specifies the interconnect to be a single twisted-pair cable (shielded or unshielded) with $120-\Omega$ characteristic impedance (Zo). Resistors equal to the characteristic impedance of the line terminate both ends of the cable to prevent signal reflections. Unterminated drop-lines connect nodes to the bus and should be kept as short as possible to minimize signal reflections.

Connectors, while not specified by the ISO 11898 standard, should have as little effect as possible on standard operating parameters such as capacitive loading. Although unshielded cable is used in many applications, data transmission circuits employing CAN transceivers are usually used in applications requiring a rugged interconnection with a wide common-mode voltage range. Therefore, shielded cable is recommended in these electronically harsh environments, and when coupled with the –2-V to 7-V common-mode range of tolerable ground noise specified in the standard, helps to ensure data integrity. The HVD251 extends data integrity beyond that of the standard with an extended –7-V to 12-V range of common-mode operation.





An eye pattern is a useful tool for measuring overall signal quality. As displayed in Figure 24, the differential signal changes logic states in two places on the display, producing an *eye*. Instead of viewing only one logic crossing on the scope, an entire *bit* of data is brought into view. The resulting eye pattern includes all effects of systemic and random distortion, and displays the time during which a signal may be considered valid.

The height of the eye above or below the receiver threshold voltage level at the sampling point is the noise margin of the system. Jitter is typically measured at the differential voltage zero-crossing during the logic state transition of a signal. Note that jitter present at the receiver threshold voltage level is considered by some to be a more effective representation of the jitter at the input of a receiver.

As the sum of skew and noise increases, the eye closes and data is corrupted. Closing the width decreases the time available for accurate sampling, and lowering the height enters the 900 mV or 500 mV threshold of a receiver.

Different sources induce noise onto a signal. The more obvious noise sources are the components of a transmission circuit themselves; the signal transmitter, traces and cables, connectors, and the receiver. Beyond that, there is a termination dependency, cross-talk from clock traces and other proximity effects, V_{CC} and ground bounce, and electromagnetic interference from nearby electrical equipment.

The balanced receiver inputs of the HVD251 mitigate most sources of signal corruption, and when used with a quality shielded twisted-pair cable, help ensure data integrity.

Typical Application

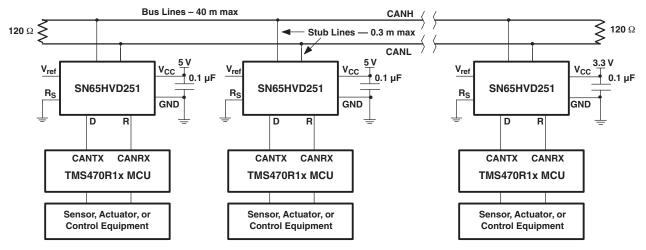


Figure 25. Typical HVD251 Application



6-Feb-2020

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
SN65HVD251QDRQ1	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	NIPDAU	Level-1-260C-UNLIM	-40 to 125	251Q1	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF SN65HVD251-Q1 :



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PACKAGE OPTION ADDENDUM

6-Feb-2020

Catalog: SN65HVD251

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

D0008A



PACKAGE OUTLINE

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.

- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



D0008A

EXAMPLE BOARD LAYOUT

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



D0008A

EXAMPLE STENCIL DESIGN

SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



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